

FIG. 1A

PATTERNED PHASE RETARDER - THIN-FILM
PATTERNED TO PRODUCE HIGHER ORDER

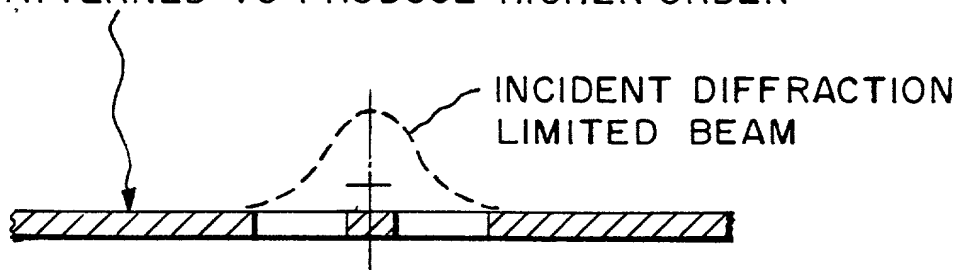


FIG. 1B

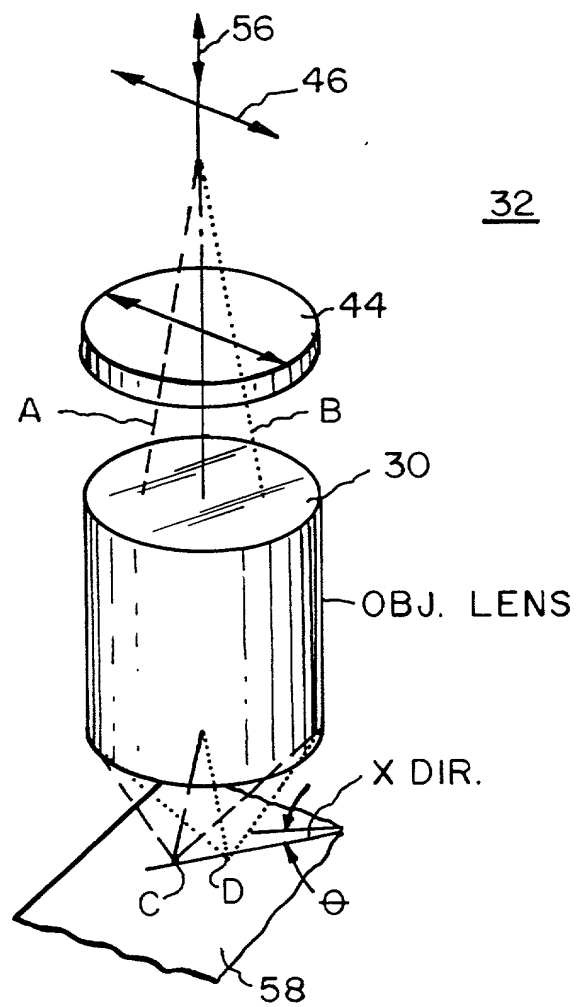


FIG. 2

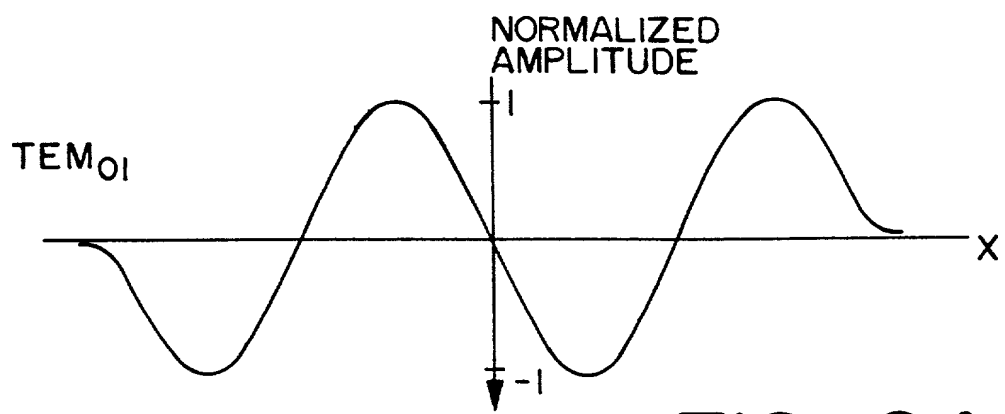


FIG. 2A

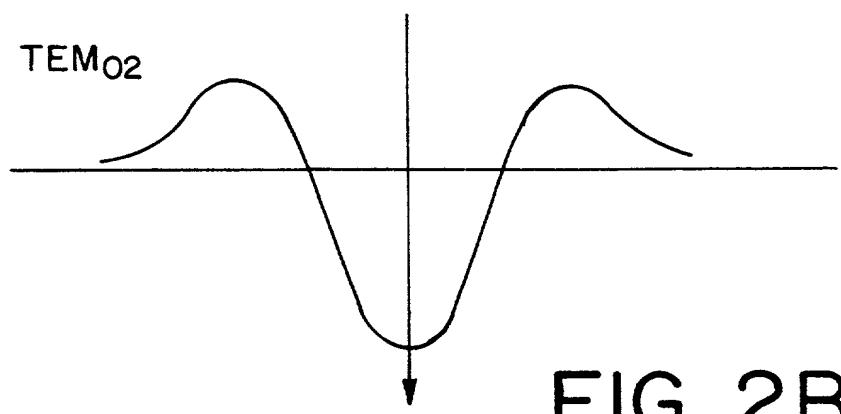


FIG. 2B

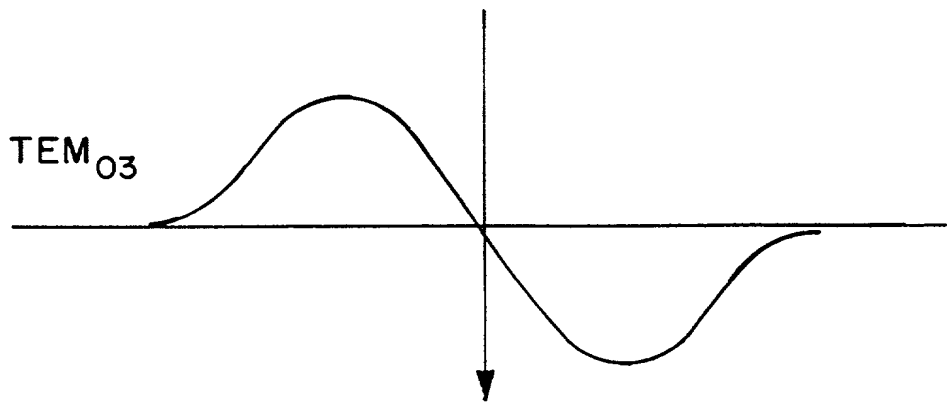


FIG. 2C

FIG. 2A

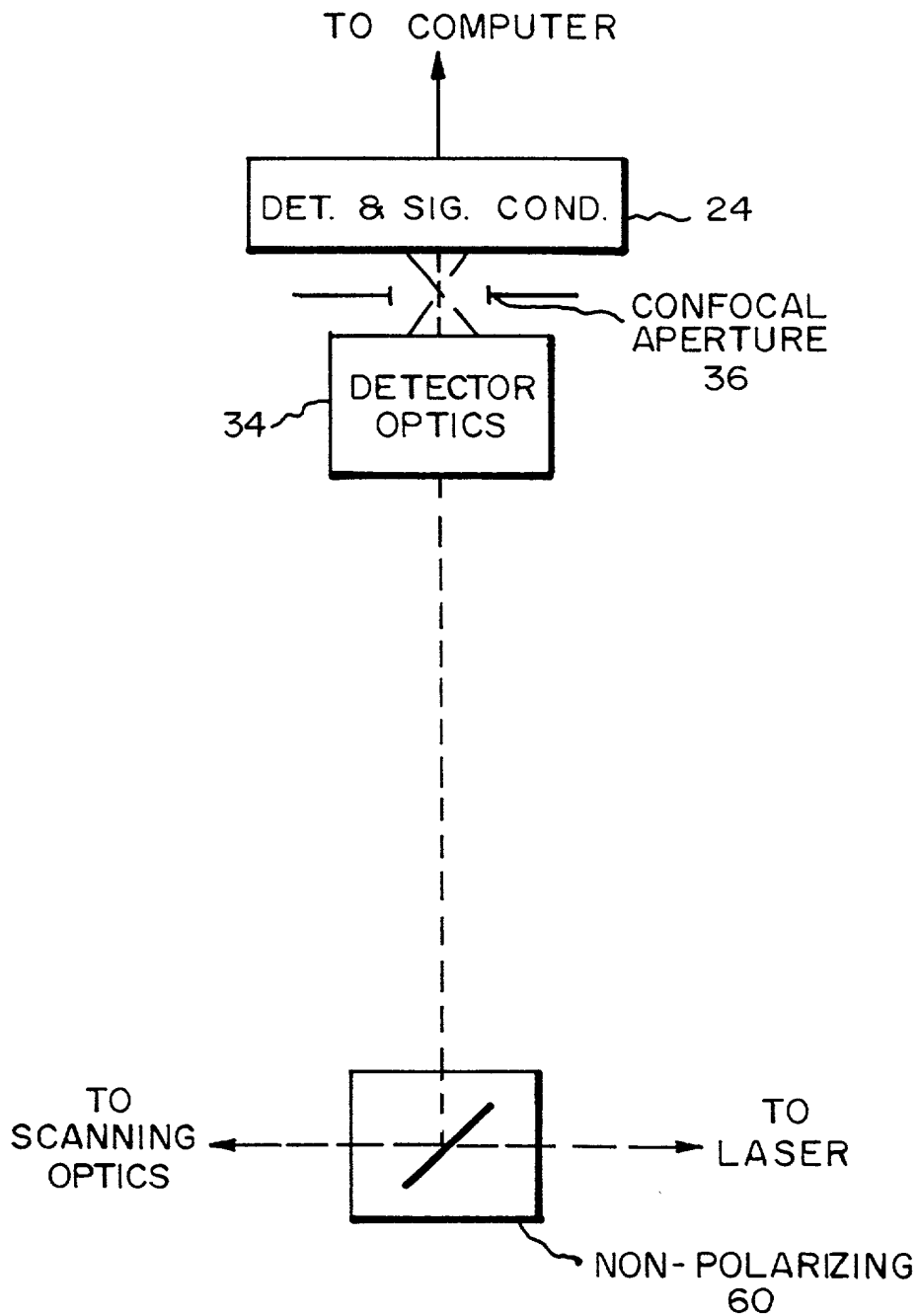


FIG. 3

FIG. 4 is a schematic diagram of an optical measurement system. The system includes a low coherence source 230, a detector and signal conditioner 245, a computer controller and data collector 260, and a display printer recorder 270. The optical path includes a beam splitter 240, a reference mirror 250, a reference actuator 255, a quarter-wave plate 205, an objective 210, and an X-Z scanning actuator 225. The system is used for measuring the surface topography of a sample 215.

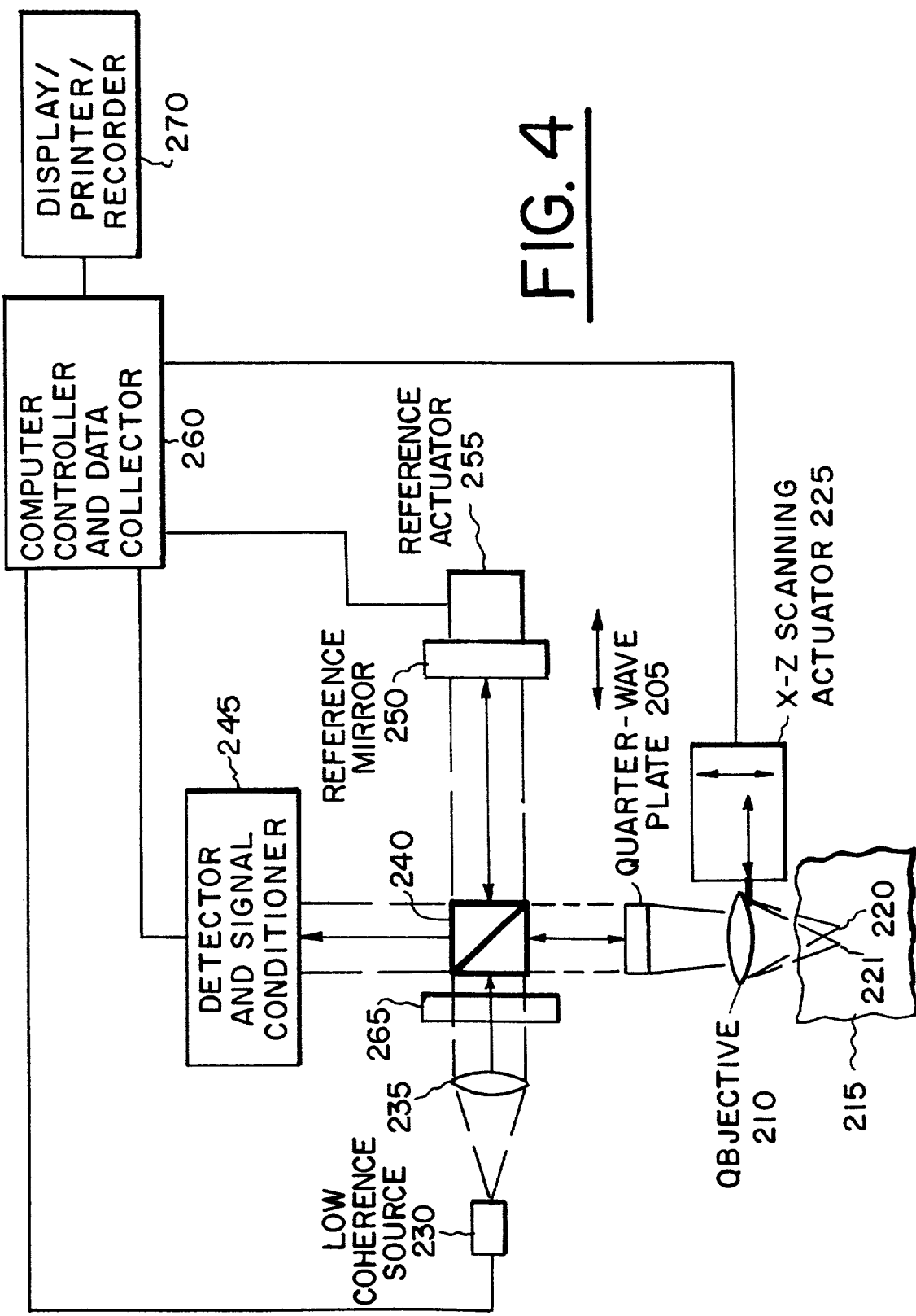


FIG. 4